

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,073	TAKIZAWA, TERUO	
Examiner	Art Unit	

Kevin Quinto

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-	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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